

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Ryosuke MESHII et al. Group Art Unit: 2817

Appln. No. : 10/599,396 Examiner: not yet assigned

(National Stage of PCT/JP2005/022747)

I.A. Filed : December 12, 2005 Confirmation No.: 8147

For : SEMICONDUCTOR PHYSICAL QUANTITY SENSOR OF

ELECTROSTATIC CAPACITANCE TYPE AND METHOD FOR

MANUFACTURING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop Amendment
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby bring to the attention of the Examiner the following information.

The following documents were cited in an International Search Report with respect to International Patent Application No. PCT/JP2005/022747, of which the present application is the U.S. National Stage Application. A copy of the International Search Report has been filed concurrently with the present application and should thus have been brought to the attention of the Examiner.

(1) Japanese Laid-Open Patent Publication No. HEI 9-196700 A, together with an English Language Abstract of the same;

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(2) Japanese Laid-Open Patent Publication No. HEI 10-178181 A, together with an English Language Abstract of the same.

The relevance of the documents cited in the International Search Report, as ascertained with respect to the International claims by the International Examiner, is set forth in the International Search Report.

Applicants further submit the following documents:

- (3) Japanese Laid-Open Patent Publication No. HEI 10-90300 A, together with an English Language Abstract of the same; and
- (4) Japanese Laid-Open Patent Publication No. HEI 6-340452 A, together with an English language Abstract of the same.

Applicants note that the Japanese documents (1), (3) and (4) are cited beginning at page 2 of the specification of the above-captioned application

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of above-noted foreign documents, including the noted English language Abstracts, are attached hereto, and are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

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Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted, Ryosuke MESHII et al.

Joshua M. Povsner

Bruce H. Bernstein Reg. No. 29,027

December 18, 2006 GREENBLUM & BERNSTEIN, P.L.C. 1950 Roland Clarke Place Reston, VA 20191 (703) 716-1191

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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.